## ┐Schlumberger Private

## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE In re Application of: Barber et al. Serial No.: 10/707,427 Filed: December 12, 2003 IN THE UNITED STATES PATENT AND TRADEMARK OFFICE Docket No.: 20.2891 Group Art Unit: Confirmation: 1426

For: Method for Determining Sonde Error for an Induction or Propagation Tool with Transverse or Triaxial Arrays

CERTIFICATE OF MAILING

) Examiner:

I hereby certify that this correspondence (along with any document referenced as being attached or enclosed hereto) is being deposited with the United States Postal Service in an envelope as First Class Mail addressed to: Commissioner for Patents, PO Pox 1450 Alexandria VA 22313-1450 on this date by the

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## INFORMATION DISCLOSURE STATEMENT

Dear Sir:

The following documents on the Form PTO-1449 are submitted to the United States Patent and Trademark Office under provisions of 37 CFR 1.97-1.98. A copy of each reference is enclosed.

Please charge any necessary fees to the deposit account for Schlumberger Technology Corporation, Account No. 19-0610.

Respectfully Submitted,

Date:

Jan 16, 2004

Registration Number 46,258

Schlumberger Technology Corporation

P. O. Box 2175

Houston, TX 77252-2175 Tel: (281) 285-7325

Fax: (281) 285-4232

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LIST OF INFORMATION PROVIDED BY APPLICANT

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SERIAL NO. 10/707,427

APPLICANT: Barber et al.

FILING DATE:

GROUP

| REFERENCE           |            |   |                                 | FILING DATE:<br>December 12, 2003                         | GROUP                                  |
|---------------------|------------|---|---------------------------------|---|--|
| REFERENCE           | DESIGNAT   | ION U.S. PATENT DOCI                                    | UMENTS                          |   |  |
| Examiner<br>Initial |            | Document No.  | Date                            | Pat   | entee                                  |
|                     | AA         |   |                                 |   |  |
|                     | AB         |   |                                 |   |  |
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|                     |            | Document No.  | Date                            | Country   | Translation<br>Yes No                  |
|                     | AJ         |   |                                 |   |  |
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| OTHER INFO          | DRMATION : | PROVIDED (AUTHOR, TIT.                                  | LE, DATE, PLA                   | CE OF PUBLICATION, I                                      | PERTINENT PAGES,                       |
|                     | AR .       | Anderson et al., 'T<br>Anisotropic Formatic<br>29, 1995 | he Response ons," SPWLA 3       | of Induction Tools t<br>36 <sup>th</sup> Annual Logging S | o Dipping,<br>ymposium, June 26 -      |
|                     | AS         | Moran et al., 'Effe<br>Measurements,' Geop              | ects of Format<br>hysics Vol. 4 | ion Anisotropy on R<br>4, NO. 7 (July 1979                | esistivity-Logging<br>) pp. 1266 -1286 |

EXAMINER

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DATE CONSIDERED

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.

1. The attached cited information should not be construed as an admission that any of the above items are prior art to the

subject invention.
This is not a representation that a search has been made